

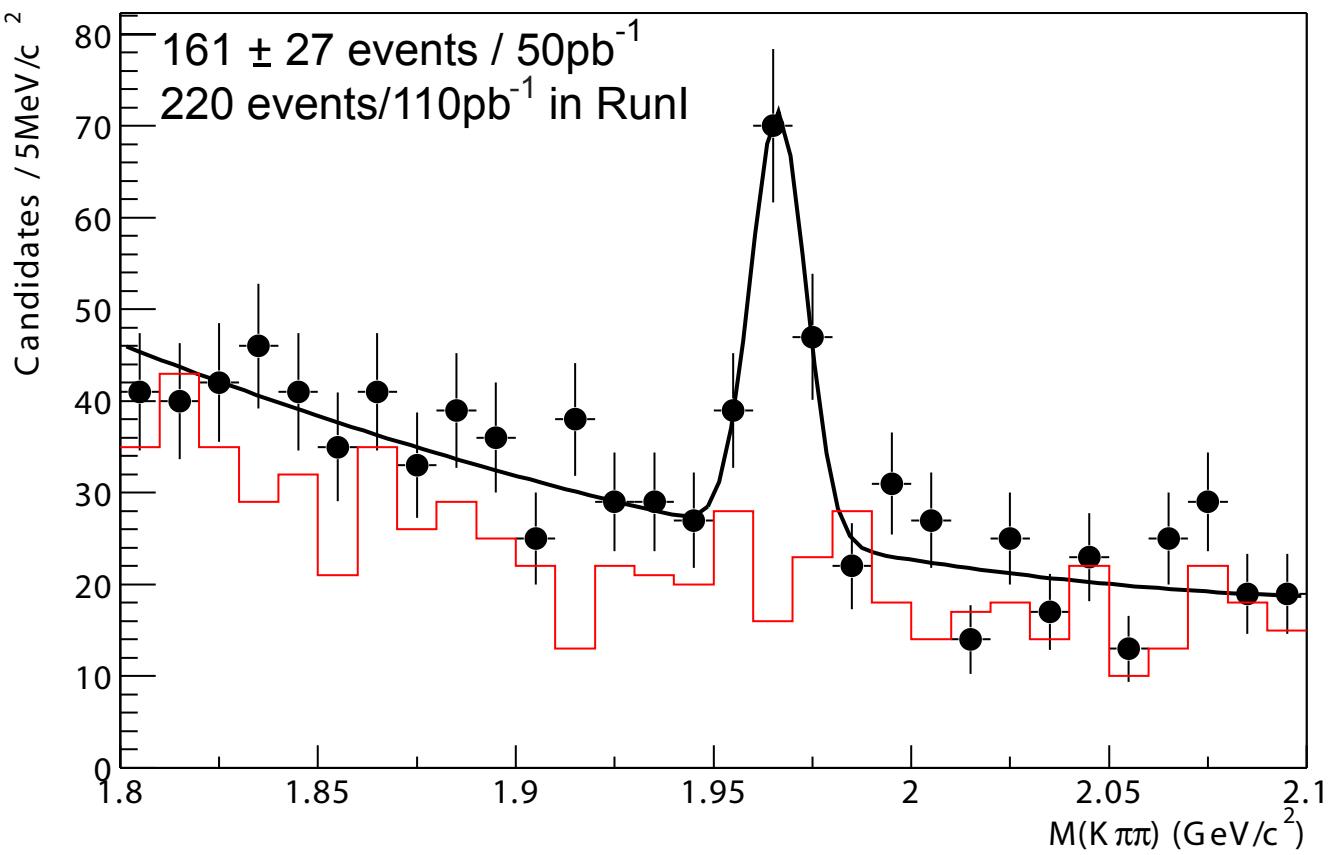
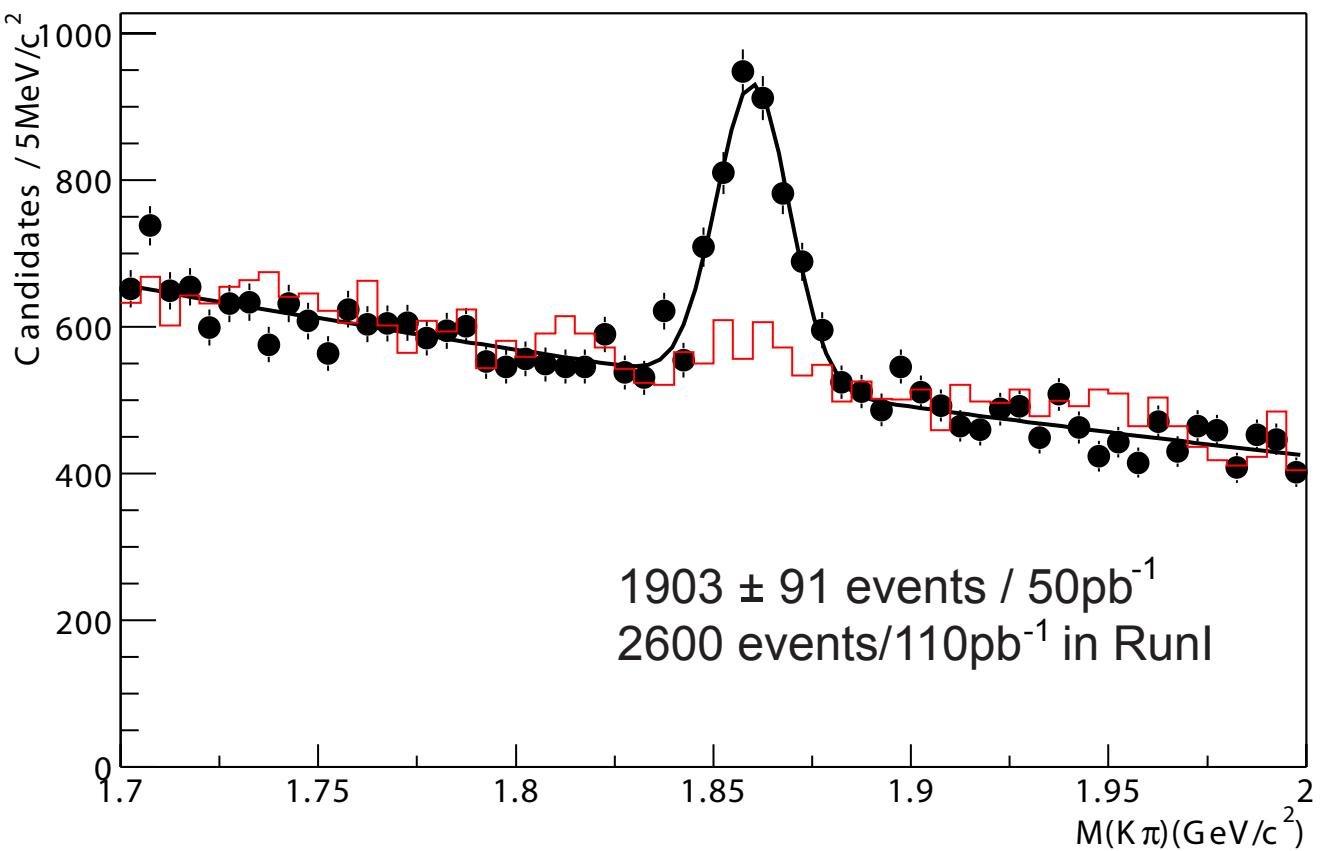
# I + charm signal in the 8GeV lepton sample

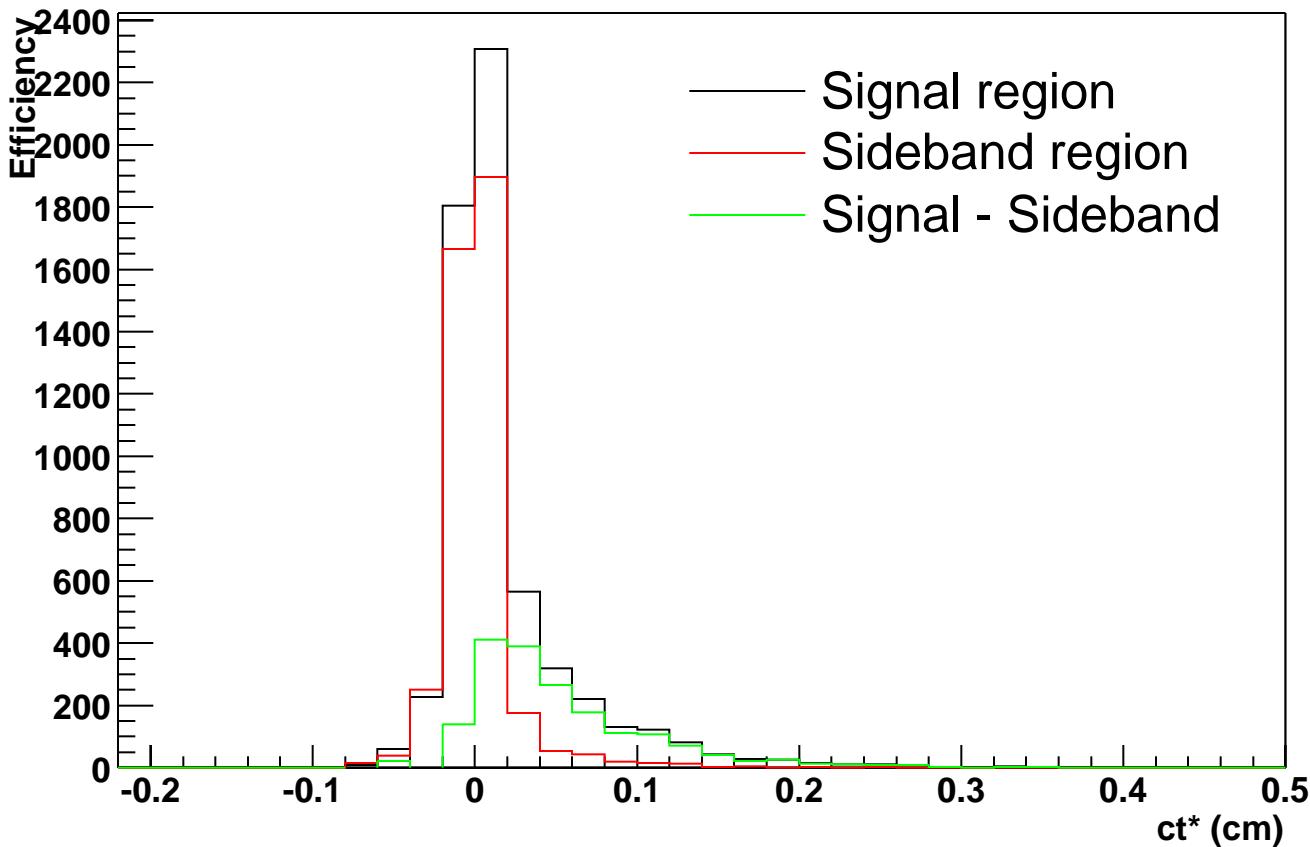
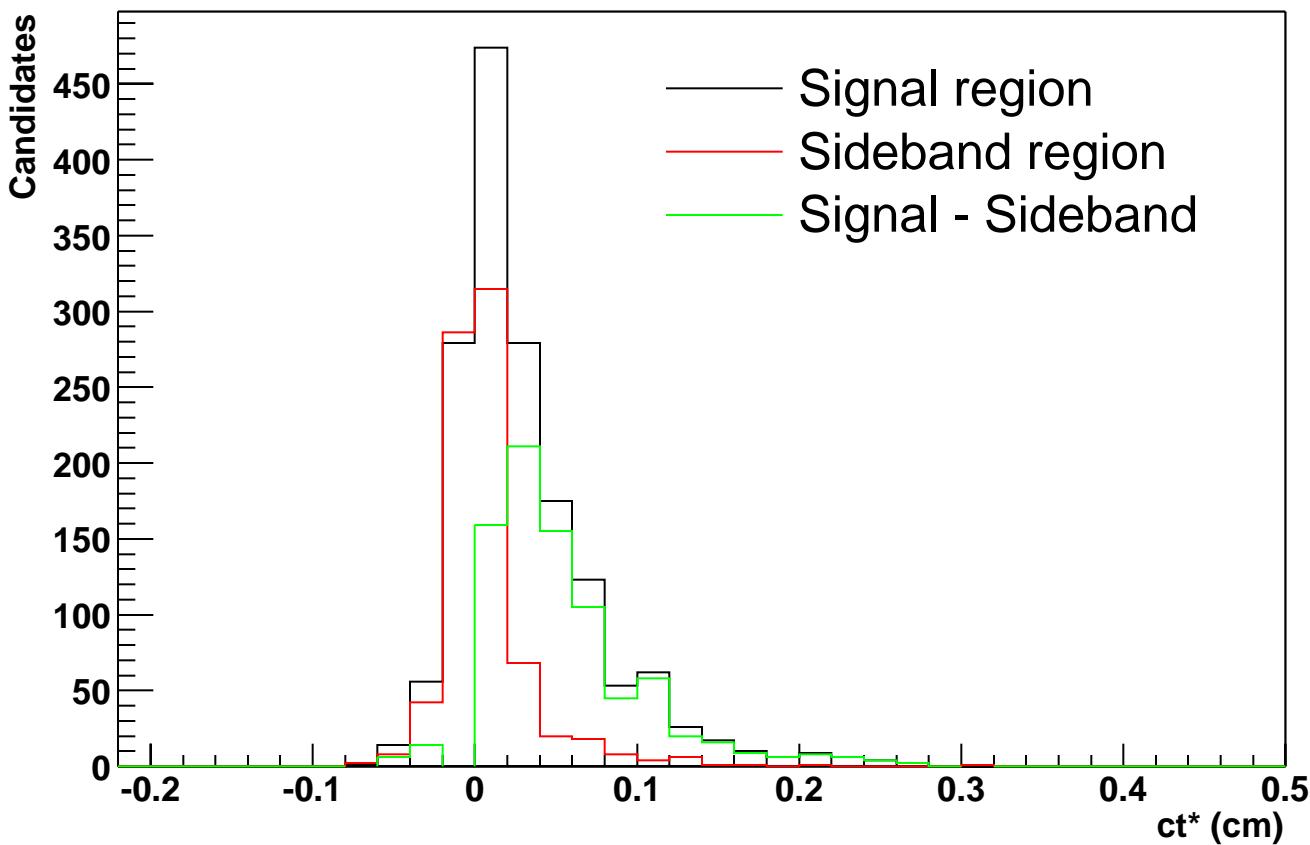
*Dec-3 2002 BCS meeting  
Satoru Uozumi*

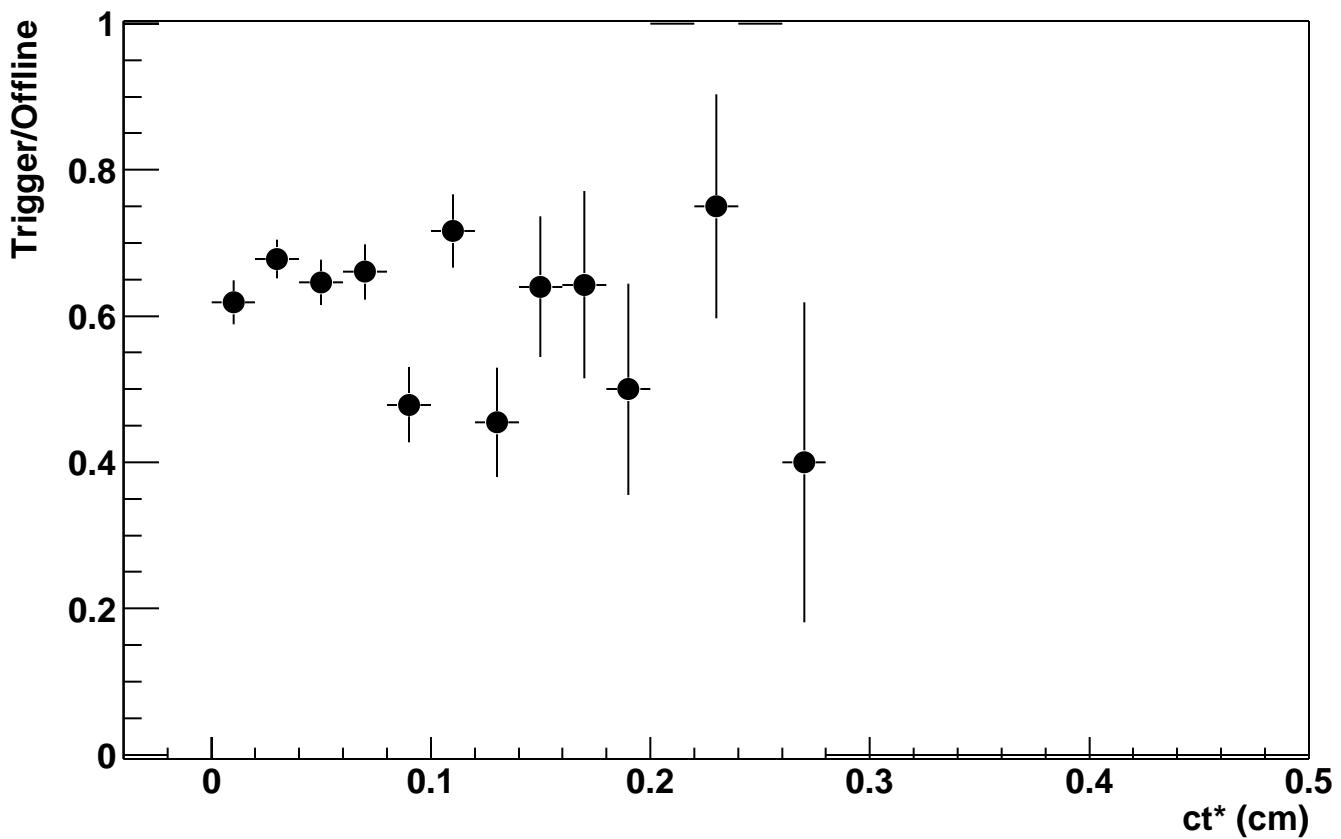
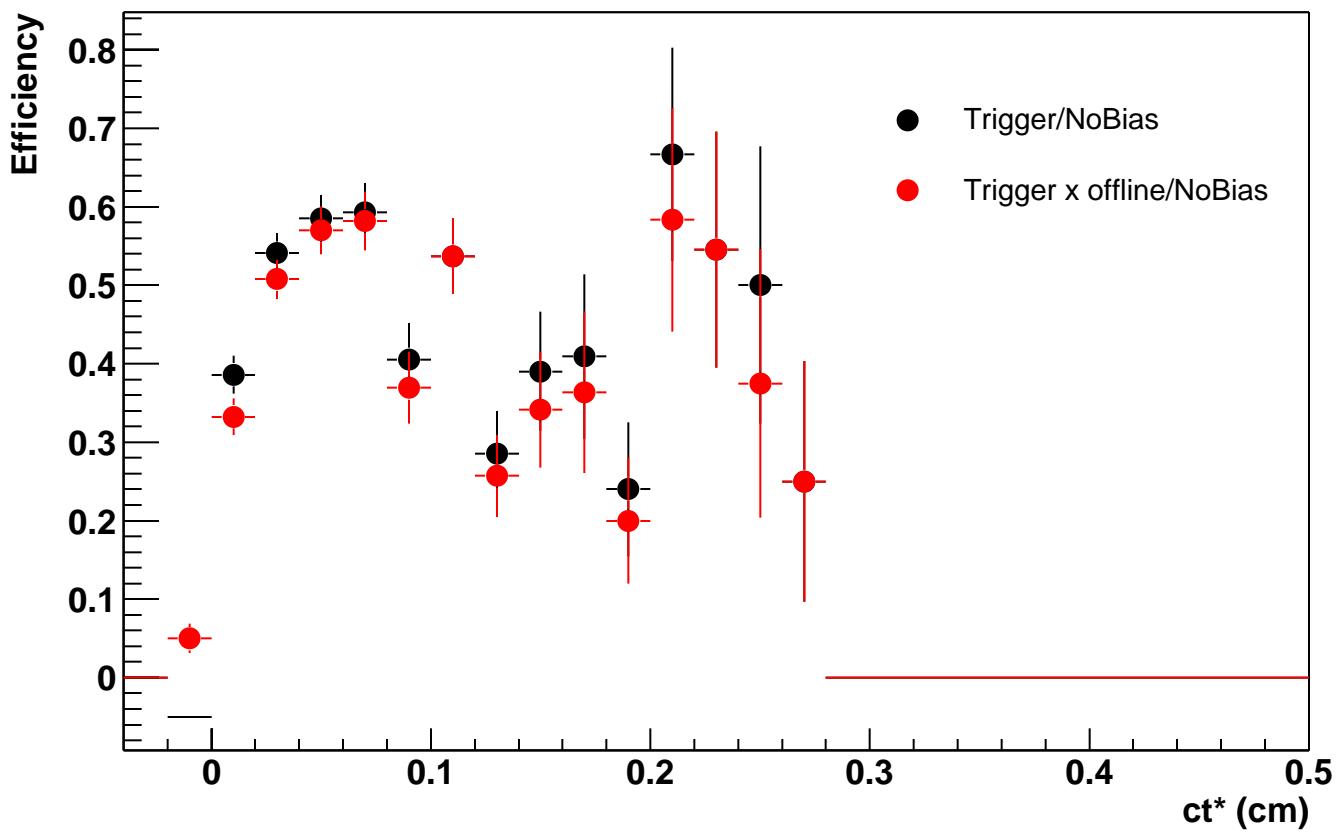
I tried to look at the lifetime bias of the SVT trigger using I+D<sup>0</sup> events in the no-biased sample (8GeV e and  $\mu$ ) and L3 trigger bit information.

## Contents

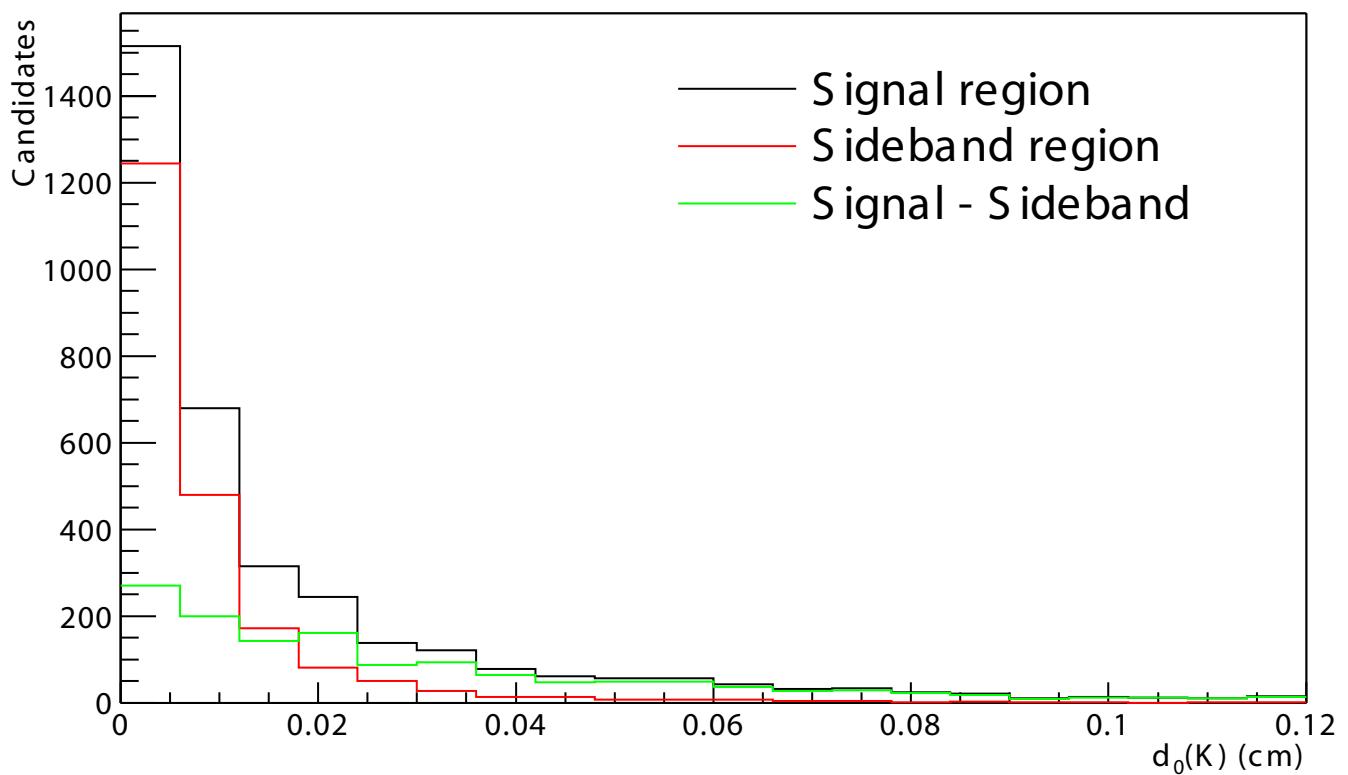
- I+D<sup>0</sup>,D<sub>s</sub> signal in the 8GeV sample
- $c t^*$  efficiency curve
- $d_0$  efficiency curve for the D0 daughter tracks



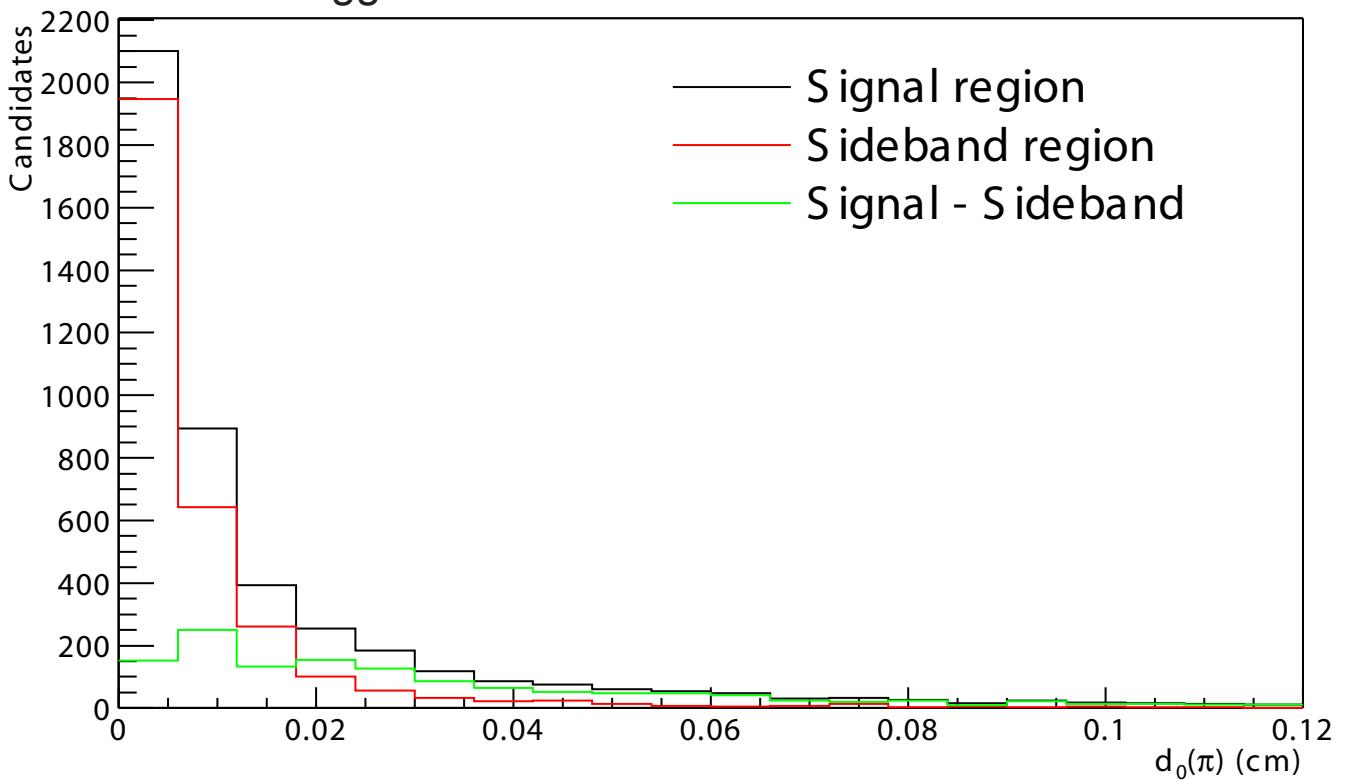
**NoBiased****I+SVT trigger hit**

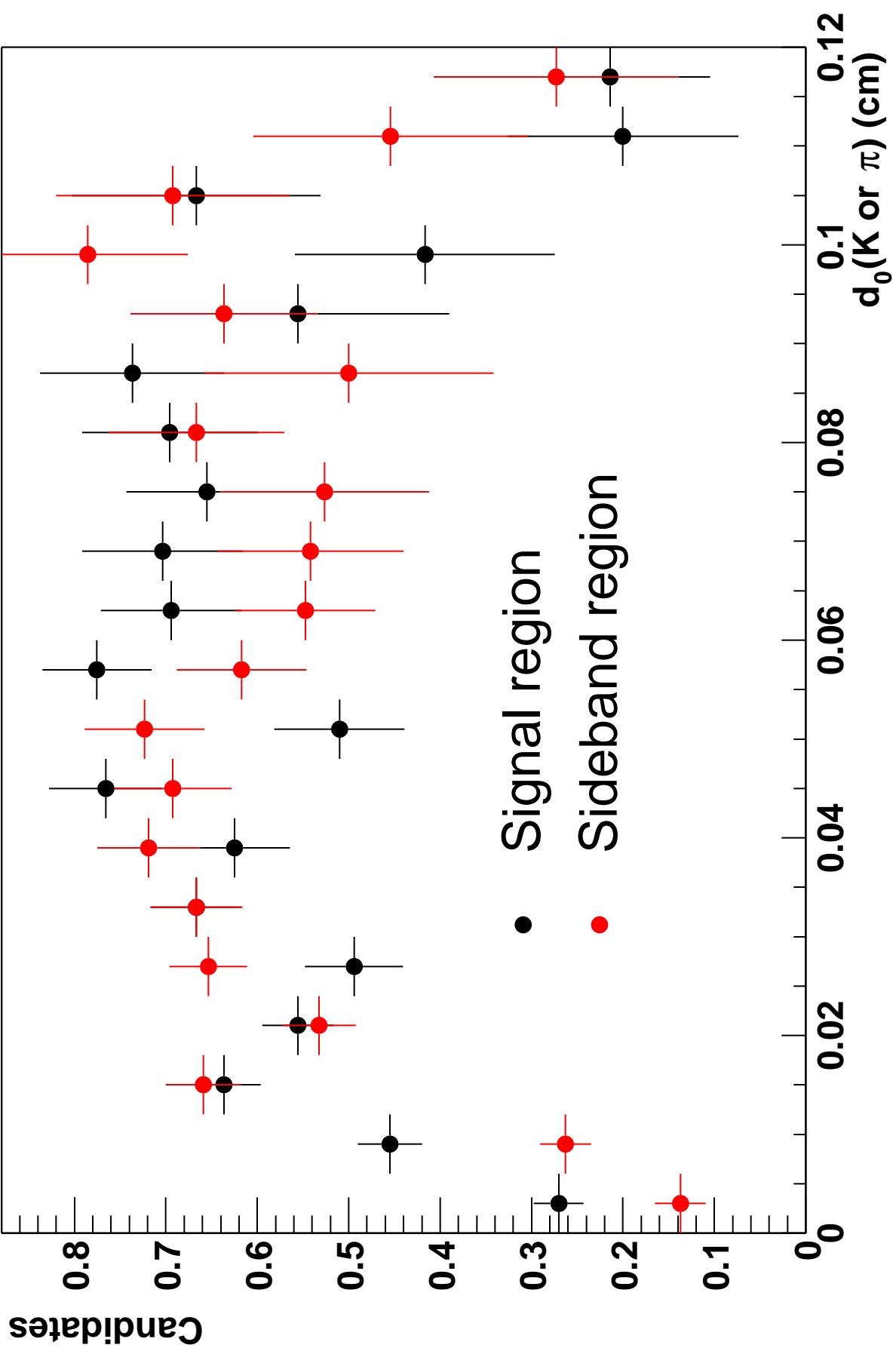


## No Biased



## I+SVT trigger hit





# Conclusion

I looked at the 8GeV sample and found  
I+D<sup>0</sup>, Ds signal as much as 50% larger  
yield than Run I.  
(mainly coming from the increase of  
silicon coverage)

ct\* and do efficiency look good.  
We will compare it with the realistic  
monte carlo sample.